



Welcome to E-XFL.COM

Understanding <u>Embedded - FPGAs (Field</u> <u>Programmable Gate Array)</u>

Embedded - FPGAs, or Field Programmable Gate Arrays, are advanced integrated circuits that offer unparalleled flexibility and performance for digital systems. Unlike traditional fixed-function logic devices, FPGAs can be programmed and reprogrammed to execute a wide array of logical operations, enabling customized functionality tailored to specific applications. This reprogrammability allows developers to iterate designs quickly and implement complex functions without the need for custom hardware.

Applications of Embedded - FPGAs

The versatility of Embedded - FPGAs makes them indispensable in numerous fields. In telecommunications.

Details

Product Status	Active
Number of LABs/CLBs	-
Number of Logic Elements/Cells	-
Total RAM Bits	110592
Number of I/O	235
Number of Gates	600000
Voltage - Supply	1.14V ~ 1.575V
Mounting Type	Surface Mount
Operating Temperature	0°C ~ 85°C (TJ)
Package / Case	484-BGA
Supplier Device Package	484-FPBGA (23x23)
Purchase URL	https://www.e-xfl.com/product-detail/microchip-technology/a3p600l-1fgg484

Email: info@E-XFL.COM

Address: Room A, 16/F, Full Win Commercial Centre, 573 Nathan Road, Mongkok, Hong Kong

ProASIC3L FPGA Fabric User's Guide

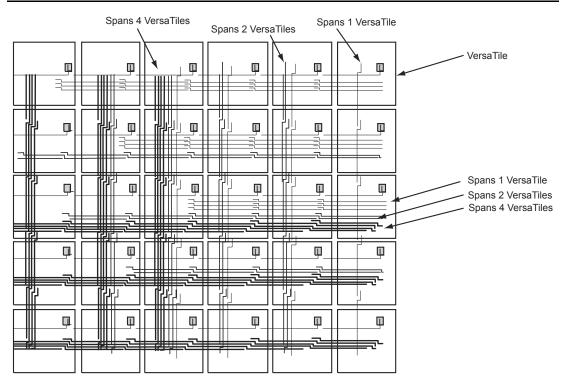


Figure 1-11 • Efficient Long-Line Resources

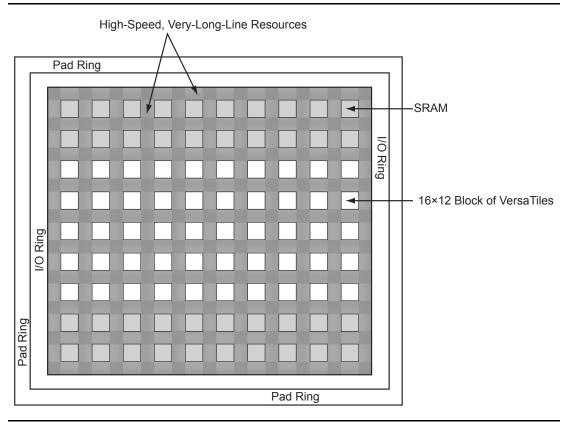


Figure 1-12 • Very-Long-Line Resources

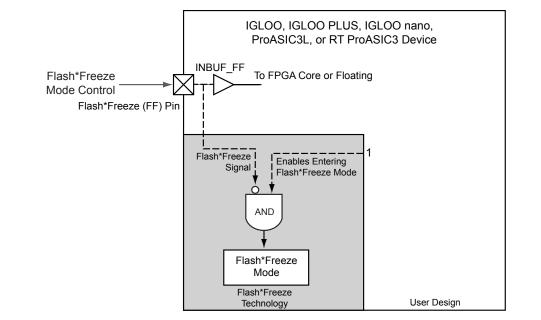


Figure 2-1 shows the concept of FF pin control in Flash*Freeze mode type 1.

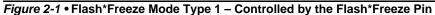


Figure 2-2 shows the timing diagram for entering and exiting Flash*Freeze mode type 1.

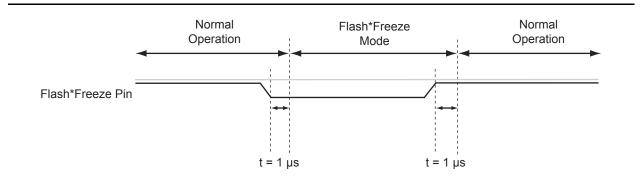


Figure 2-2 • Flash*Freeze Mode Type 1 – Timing Diagram

ProASIC3L FPGA Fabric User's Guide

Date	Changes	Page
v2.1 (October 2008)	The title changed from "Flash*Freeze Technology and Low Power Modes in IGLOO, IGLOO PLUS, and ProASIC3L Devices" to Actel's Flash*Freeze Technology and Low Power Modes."	N/A
	The "Flash Families Support the Flash*Freeze Feature" section was updated.	22
	Significant changes were made to this document to support Libero IDE v8.4 and later functionality. RT ProASIC3 device support information is new. In addition to the other major changes, the following tables and figures were updated or are new: Figure 2-3 • Flash*Freeze Mode Type 2 – Controlled by Flash*Freeze Pin and	
	Internal Logic (LSICC signal) – updated Figure 2-5 • Narrow Clock Pulses During Flash*Freeze Entrance and Exit – new	27
	Figure 2-10 • Flash*Freeze Management IP Block Diagram – new	30
	Figure 2-11 • FSM State Diagram – new	37
	Table 2-6 • IGLOO nano and IGLOO PLUS Flash*Freeze Mode (type 1 and type 2)—I/O Pad State – updated	38 29
	Please review the entire document carefully.	20
v1.3 (June 2008)	The family description for ProASIC3L in Table 2-1 • Flash-Based FPGAs was updated to include 1.5 V.	22
v1.2 (March 2008)	The part number for this document was changed from 51700094-003-1 to 51700094-004-2.	N/A
	The title of the document was changed to "Flash*Freeze Technology and Low Power Modes in IGLOO, IGLOO PLUS, and ProASIC3L Devices."	N/A
	The "Flash*Freeze Technology and Low Power Modes" section was updated to remove the parenthetical phrase, "from 25 μ W," in the second paragraph. The following sentence was added to the third paragraph: "IGLOO PLUS has an additional feature when operating in Flash*Freeze mode, allowing it to retain I/O states as well as SRAM and register states."	21
	The "Power Conservation Techniques" section was updated to add V_{JTAG} to the parenthetical list of power supplies that should be tied to the ground plane if unused. Additional information was added regarding how the software configures unused I/Os.	2-1
	Table 2-1 • Flash-Based FPGAs and the accompanying text was updated to include the IGLOO PLUS family. The "IGLOO Terminology" section and "ProASIC3 Terminology" section are new.	22
	The "Flash*Freeze Mode" section was revised to include that I/O states are preserved in Flash*Freeze mode for IGLOO PLUS devices. The last sentence in the second paragraph was changed to, "If the FF pin is not used, it can be used as a regular I/O." The following sentence was added for Flash*Freeze mode type 2: "Exiting the mode is controlled by either the FF pin OR the user-defined LSICC signal."	24
	The "Flash*Freeze Type 1: Control by Dedicated Flash*Freeze Pin" section was revised to change instructions for implementing this mode, including instructions for implementation with Libero IDE v8.3.	24
	Figure 2-1 • Flash*Freeze Mode Type 1 – Controlled by the Flash*Freeze Pin was updated.	25
	The "Flash*Freeze Type 2: Control by Dedicated Flash*Freeze Pin and Internal Logic" section was renamed from "Type 2 Software Implementation."	26
	The "Type 2 Software Implementation for Libero IDE v8.3" section is new.	2-6



Global Resources in Low Power Flash Devices

	able 3-3 • Quadrant Global Pin Name (continued)					
Differential I/O Pairs	GAAO/IOuxwByVz	The output of the different pair will drive the global.				
	GAA1/IOuxwByVz					
	GABO/IOuxwByVz	The output of the different pair will drive the global.				
	GAB1/IOuxwByVz					
	GACO/IOuxwByVz	The output of the different pair will drive the global.				
	GAC1/IOuxwByVz					
	GBAO/IOuxwByVz	The output of the different pair will drive the global.				
	GBA1/IOuxwByVz					
	GBBO/IOuxwByVz	The output of the different pair will drive the global.				
	GBB1/IOuxwByVz					
	GBCO/IOuxwByVz	The output of the different pair will drive the global.				
	GBC1/IOuxwByVz					
	GDAO/IOuxwByVz	The output of the different pair will drive the global.				
	GDA1/IOuxwByVz					
	GDBO/IOuxwByVz	The output of the different pair will drive the global.				
	GDB1/IOuxwByVz					
	GDCO/IOuxwByVz	The output of the different pair will drive the global.				
	GDC1/IOuxwByVz					
	GEAO/IOuxwByVz	The output of the different pair will drive the global.				
	GEA1/IOuxwByVz					
	GEBO/IOuxwByVz	The output of the different pair will drive the global.				
	GEB1/IOuxwByVz					
	GECO/IOuxwByVz	The output of the different pair will drive the global.				
	GEC1/IOuxwByVz					

Table 3-3 • Quadrant Global Pin Name (continued)

Note: Only one of the I/Os can be directly connected to a quadrant at a time.

Unused Global I/O Configuration

The unused clock inputs behave similarly to the unused Pro I/Os. The Microsemi Designer software automatically configures the unused global pins as inputs with pull-up resistors if they are not used as regular I/O.

I/O Banks and Global I/O Standards

In low power flash devices, any I/O or internal logic can be used to drive the global network. However, only the global macro placed at the global pins will use the hardwired connection between the I/O and global network. Global signal (signal driving a global macro) assignment to I/O banks is no different from regular I/O assignment to I/O banks with the exception that you are limited to the pin placement location available. Only global signals compatible with both the VCCI and VREF standards can be assigned to the same bank.

Spine Architecture

The low power flash device architecture allows the VersaNet global networks to be segmented. Each of these networks contains spines (the vertical branches of the global network tree) and ribs that can reach all the VersaTiles inside its region. The nine spines available in a vertical column reside in global networks with two separate regions of scope: the quadrant global network, which has three spines, and the chip (main) global network, which has six spines. Note that the number of quadrant globals and globals/spines per tree varies depending on the specific device. Refer to Table 3-4 for the clocking resources available for each device. The spines are the vertical branches of the global network tree, shown in Figure 3-3 on page 50. Each spine in a vertical column of a chip (main) global network is further divided into two spine segments of equal lengths: one in the top and one in the bottom half of the die (except in 10 k through 30 k gate devices).

Top and bottom spine segments radiating from the center of a device have the same height. However, just as in the ProASIC^{PLUS®} family, signals assigned only to the top and bottom spine cannot access the middle two rows of the die. The spines for quadrant clock networks do not cross the middle of the die and cannot access the middle two rows of the architecture.

Each spine and its associated ribs cover a certain area of the device (the "scope" of the spine; see Figure 3-3 on page 50). Each spine is accessed by the dedicated global network MUX tree architecture, which defines how a particular spine is driven—either by the signal on the global network from a CCC, for example, or by another net defined by the user. Details of the chip (main) global network spine-selection MUX are presented in Figure 3-8 on page 60. The spine drivers for each spine are located in the middle of the die.

Quadrant spines can be driven from user I/Os or an internal signal from the north and south sides of the die. The ability to drive spines in the quadrant global networks can have a significant effect on system performance for high-fanout inputs to a design. Access to the top quadrant spine regions is from the top of the die, and access to the bottom quadrant spine regions is from the bottom of the die. The A3PE3000 device has 28 clock trees and each tree has nine spines; this flexible global network architecture enables users to map up to 252 different internal/external clocks in an A3PE3000 device.

ProASIC3/ ProASIC3L Devices	IGLOO Devices	Chip Globals	Quadrant Globals (4×3)	Clock Trees	Globals/ Spines per Tree		VersaTiles in Each Tree	Total VersaTiles	Rows in Each Spine
A3PN010	AGLN010	4	0	1	0	0	260	260	4
A3PN015	AGLN015	4	0	1	0	0	384	384	6
A3PN020	AGLN020	4	0	1	0	0	520	520	6
A3PN060	AGLN060	6	12	4	9	36	384	1,536	12
A3PN125	AGLN125	6	12	8	9	72	384	3,072	12
A3PN250	AGLN250	6	12	8	9	72	768	6,144	24
A3P015	AGL015	6	0	1	9	9	384	384	12
A3P030	AGL030	6	0	2	9	18	384	768	12
A3P060	AGL060	6	12	4	9	36	384	1,536	12
A3P125	AGL125	6	12	8	9	72	384	3,072	12
A3P250/L	AGL250	6	12	8	9	72	768	6,144	24
A3P400	AGL400	6	12	12	9	108	768	9,216	24
A3P600/L	AGL600	6	12	12	9	108	1,152	13,824	36
A3P1000/L	AGL1000	6	12	16	9	144	1,536	24,576	48
A3PE600/L	AGLE600	6	12	12	9	108	1,120	13,440	35
A3PE1500		6	12	20	9	180	1,888	37,760	59
A3PE3000/L	AGLE3000	6	12	28	9	252	2,656	74,368	83

Table 3-4 • Globals/Spines/Rows for IGLOO and ProASIC3 Devices

Global Resources in Low Power Flash Devices

Using Clock Aggregation

Clock aggregation allows for multi-spine clock domains to be assigned using hardwired connections, without adding any extra skew. A MUX tree, shown in Figure 3-8, provides the necessary flexibility to allow long lines, local resources, or I/Os to access domains of one, two, or four global spines. Signal access to the clock aggregation system is achieved through long-line resources in the central rib in the center of the die, and also through local resources in the north and south ribs, allowing I/Os to feed directly into the clock system. As Figure 3-9 indicates, this access system is contiguous.

There is no break in the middle of the chip for the north and south I/O VersaNet access. This is different from the quadrant clocks located in these ribs, which only reach the middle of the rib.

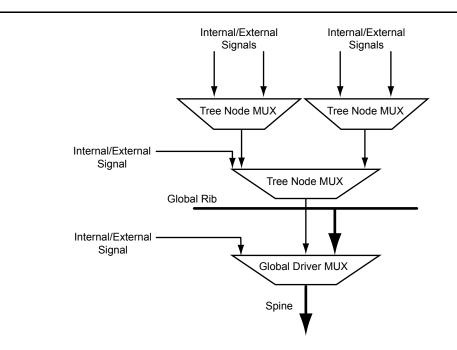


Figure 3-8 • Spine Selection MUX of Global Tree

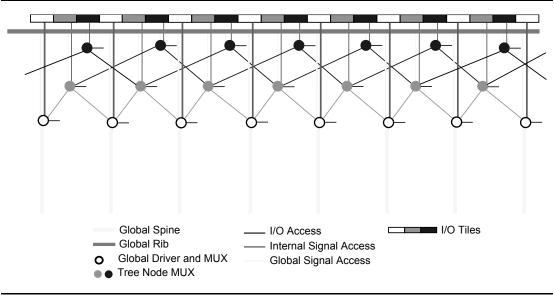


Figure 3-9 • Clock Aggregation Tree Architecture

SRAM and FIFO Memories in Microsemi's Low Power Flash Devices

Table 6-8 and Table 6-9 show the maximum potential width and depth configuration for each device. Note that 15 k and 30 k gate devices do not support RAM or FIFO.

Device			Maximu	um Potential Width ¹	Maximum Potential	Depth ²
IGLOO IGLOO nano IGLOO PLUS	ProASIC3 ProASIC3 nano ProASIC3L	RAM Block s	Depth	Width	Depth	Width
AGL060 AGLN060 AGLP060	A3P060 A3PN060	4	256	72 (4×18)	16,384 (4,096×4)	1
AGL125 AGLN125 AGLP125	A3P125 A3PN125	8	256	144 (8×18)	32,768 (4,094×8)	1
AGL250 AGLN250	A3P250/L A3PN250	8	256	144 (8×18)	32,768 (4,096×8)	1
AGL400	A3P400	12	256	216 (12×18)	49,152 (4,096×12)	1
AGL600	A3P600/L	24	256	432 (24×18)	98,304 (4,096×24)	1
AGL1000	A3P1000/L	32	256	576 (32×18)	131,072 (4,096×32)	1
AGLE600	A3PE600	24	256	432 (24×18)	98,304 (4,096×24)	1
	A3PE1500	60	256	1,080 (60×18)	245,760 (4,096×60)	1
AGLE3000	A3PE3000/L	112	256	2,016 (112×18)	458,752 (4,096×112)	1

Notes:

1. Maximum potential width uses the two-port configuration.

2. Maximum potential depth uses the dual-port configuration.

Table 6-9 • Memory Availability per Fusion Device

		Maximu	m Potential Width ¹	Maximum Potential	Depth ²
Device	RAM Blocks	Depth	Width	Depth	Width
AFS090	6	256	108 (6×18)	24,576 (4,094×6)	1
AFS250	8	256	144 (8×18)	32,768 (4,094×8)	1
AFS600	24	256	432 (24×18)	98,304 (4,096×24)	1
AFS1500	60	256	1,080 (60×18)	245,760 (4,096×60)	1

Notes:

1. Maximum potential width uses the two-port configuration.

2. Maximum potential depth uses the dual-port configuration.

7 – I/O Structures in IGLOO and ProASIC3 Devices

Introduction

Low power flash devices feature a flexible I/O structure, supporting a range of mixed voltages (1.2 V, 1.5 V, 1.8 V, 2.5 V, and 3.3 V) through bank-selectable voltages. IGLOO,[®] ProASIC3[®]L, and ProASIC3 families support Standard, Standard Plus, and Advanced I/Os.

Users designing I/O solutions are faced with a number of implementation decisions and configuration choices that can directly impact the efficiency and effectiveness of their final design. The flexible I/O structure, supporting a wide variety of voltages and I/O standards, enables users to meet the growing challenges of their many diverse applications. Libero SoC software provides an easy way to implement I/Os that will result in robust I/O design.

This document first describes the two different I/O types in terms of the standards and features they support. It then explains the individual features and how to implement them in Libero SoC.

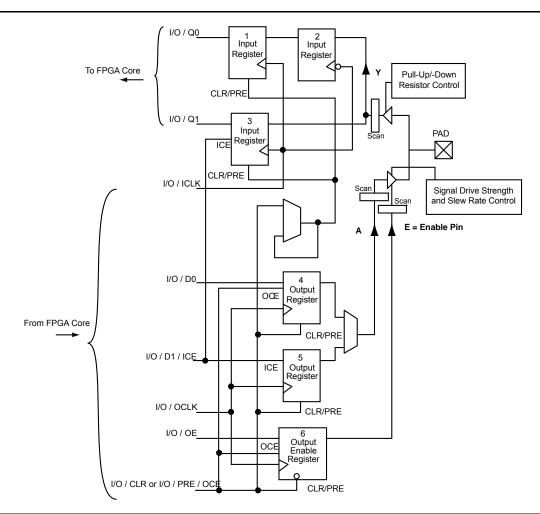


Figure 7-1 • DDR Configured I/O Block Logical Representation

I/O Structures in IGLOOe and ProASIC3E Devices

Low Power Flash Device I/O Support

The low power flash FPGAs listed in Table 8-1 support I/Os and the functions described in this document.

Table 8-1 • Flash-Based FPGAs

Series	Family [*]	Description
IGLOO	IGLOOe	Higher density IGLOO FPGAs with six PLLs and additional I/O standards
ProASIC3	ProASIC3E	Higher density ProASIC3 FPGAs with six PLLs and additional I/O standards
	ProASIC3L	ProASIC3 FPGAs supporting 1.2 V to 1.5 V with Flash*Freeze technology
	Military ProASIC3/EL	Military temperature A3PE600L, A3P1000, and A3PE3000L
	RT ProASIC3	Radiation-tolerant RT3PE600L and RT3PE3000L

Note: *The device names link to the appropriate datasheet, including product brief, DC and switching characteristics, and packaging information.

IGLOO Terminology

In documentation, the terms IGLOO series and IGLOO devices refer to all of the IGLOO devices as listed in Table 8-1. Where the information applies to only one product line or limited devices, these exclusions will be explicitly stated.

ProASIC3 Terminology

In documentation, the terms ProASIC3 series and ProASIC3 devices refer to all of the ProASIC3 devices as listed in Table 8-1. Where the information applies to only one product line or limited devices, these exclusions will be explicitly stated.

To further understand the differences between the IGLOO and ProASIC3 devices, refer to the *Industry's Lowest Power FPGAs Portfolio.*

I/O Structures in IGLOOe and ProASIC3E Devices

I/O Banks and I/O Standards Compatibility

I/Os are grouped into I/O voltage banks.

Each I/O voltage bank has dedicated I/O supply and ground voltages (VMV/GNDQ for input buffers and V_{CCI} /GND for output buffers). Because of these dedicated supplies, only I/Os with compatible standards can be assigned to the same I/O voltage bank. Table 8-3 on page 217 shows the required voltage compatibility values for each of these voltages.

There are eight I/O banks (two per side).

Every I/O bank is divided into minibanks. Any user I/O in a VREF minibank (a minibank is the region of scope of a VREF pin) can be configured as a VREF pin (Figure 8-2). Only one V_{REF} pin is needed to control the entire V_{REF} minibank. The location and scope of the V_{REF} minibanks can be determined by the I/O name. For details, see the user I/O naming conventions for "IGLOOe and ProASIC3E" on page 245. Table 8-5 on page 217 shows the I/O standards supported by IGLOOe and ProASIC3E devices, and the corresponding voltage levels.

I/O standards are compatible if they comply with the following:

- Their VCCI and VMV values are identical.
- Both of the standards need a VREF, and their VREF values are identical.
- All inputs and disabled outputs are voltage tolerant up to 3.3 V.

For more information about I/O and global assignments to I/O banks in a device, refer to the specific pin table for the device in the packaging section of the datasheet, and see the user I/O naming conventions for "IGLOOe and ProASIC3E" on page 245.

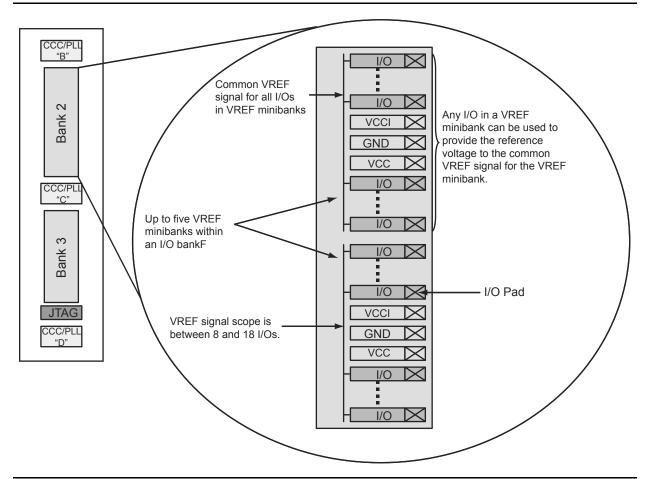
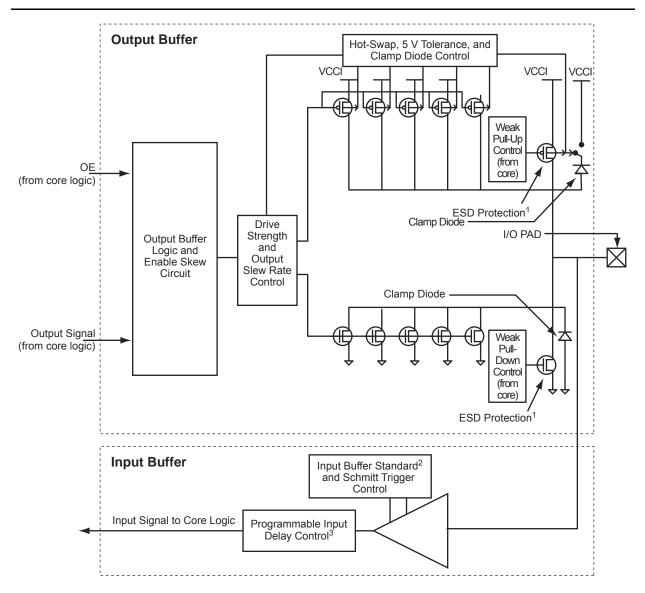


Figure 8-2 • Typical IGLOOe and ProASIC3E I/O Bank Detail Showing VREF Minibanks



I/O Structures in IGLOOe and ProASIC3E Devices



Notes:

- 1. All NMOS transistors connected to the I/O pad serve as ESD protection.
- 2. See Table 8-2 on page 215 for available I/O standards.
- 3. Programmable input delay is applicable only to ProASIC3E, IGLOOe, ProASIC3EL, and RT ProASIC3 devices.

Figure 8-5 • Simplified I/O Buffer Circuitry

I/O Registers

Each I/O module contains several input, output, and enable registers. Refer to Figure 8-5 for a simplified representation of the I/O block. The number of input registers is selected by a set of switches (not shown in Figure 8-3 on page 220) between registers to implement single-ended or differential data transmission to and from the FPGA core. The Designer software sets these switches for the user. A common CLR/PRE signal is employed by all I/O registers when I/O register combining is used. Input Register 2 does not have a CLR/PRE pin, as this register is used for DDR implementation. The I/O register combining must satisfy certain rules.



I/O Structures in IGLOOe and ProASIC3E Devices

5 V Input and Output Tolerance

IGLOO and ProASIC3 devices are both 5 V-input– and 5 V–output–tolerant if certain I/O standards are selected. Table 8-6 on page 218 shows the I/O standards that support 5 V input tolerance. Only 3.3 V LVTTL/LVCMOS standards support 5 V output tolerance. Refer to the appropriate family datasheet for detailed description and configuration information.

This feature is not shown in the I/O Attribute Editor.

5 V Input Tolerance

I/Os can support 5 V input tolerance when LVTTL 3.3 V, LVCMOS 3.3 V, LVCMOS 2.5 V, and LVCMOS 2.5 V / 5.0 V configurations are used (see Table 8-13 on page 231). There are four recommended solutions for achieving 5 V receiver tolerance (see Figure 8-10 on page 233 to Figure 8-13 on page 235 for details of board and macro setups). All the solutions meet a common requirement of limiting the voltage at the input to 3.6 V or less. In fact, the I/O absolute maximum voltage rating is 3.6 V, and any voltage above 3.6 V may cause long-term gate oxide failures.

Solution 1

The board-level design must ensure that the reflected waveform at the pad does not exceed the limits provided in the recommended operating conditions in the datasheet. This is a requirement to ensure long-term reliability.

This scheme will also work for a 3.3 V PCI/PCI-X configuration, but the internal diode should not be used for clamping, and the voltage must be limited by the two external resistors as explained below. Relying on the diode clamping would create an excessive pad DC voltage of 3.3 V + 0.7 V = 4 V.

This solution requires two board resistors, as demonstrated in Figure 8-10 on page 233. Here are some examples of possible resistor values (based on a simplified simulation model with no line effects and 10 Ω transmitter output resistance, where Rtx_out_high = [VCCI – VOH] / I_{OH} and

Example 1 (high speed, high current):

Rtx_out_high = Rtx_out_low = 10
$$\Omega$$

R1 = 36 Ω (±5%), P(r1)min = 0.069 Ω

R2 = 82 Ω (±5%), P(r2)min = 0.158 Ω

Imax_tx = 5.5 V / (82 × 0.95 + 36 × 0.95 + 10) = 45.04 mA

t_{RISE} = t_{FALL} = 0.85 ns at C_pad_load = 10 pF (includes up to 25% safety margin)

t_{RISE} = t_{FALL} = 4 ns at C_pad_load = 50 pF (includes up to 25% safety margin)

Example 2 (low-medium speed, medium current):

Rtx_out_high = Rtx_out_low = 10 Ω

R1 = 220 Ω (±5%), P(r1)min = 0.018 Ω

R2 = 390 Ω (±5%), P(r2)min = 0.032 Ω

Imax_tx = 5.5 V / (220 × 0.95 + 390 × 0.95 + 10) = 9.17 mA

t_{RISE} = t_{FALL} = 4 ns at C_pad_load = 10 pF (includes up to 25% safety margin)

t_{RISE} = t_{FALL} = 20 ns at C_pad_load = 50 pF (includes up to 25% safety margin)

Other values of resistors are also allowed as long as the resistors are sized appropriately to limit the voltage at the receiving end to 2.5 V < Vin(rx) < 3.6 V when the transmitter sends a logic 1. This range of Vin_dc(rx) must be assured for any combination of transmitter supply (5 V ± 0.5 V), transmitter output resistance, and board resistor tolerances.

Temporary overshoots are allowed according to the overshoot and undershoot table in the datasheet.

User I/O Naming Convention

IGLOOe and ProASIC3E

Due to the comprehensive and flexible nature of IGLOOe and ProASIC3E device user I/Os, a naming scheme is used to show the details of each I/O (Figure 8-20 on page 246). The name identifies to which I/O bank it belongs, as well as the pairing and pin polarity for differential I/Os.

I/O Nomenclature = FF/Gmn/IOuxwByVz

Gmn is only used for I/Os that also have CCC access—i.e., global pins.

- FF = Indicates the I/O dedicated for the Flash*Freeze mode activation pin in IGLOOe only
- G = Global
- m = Global pin location associated with each CCC on the device: A (northwest corner), B (northeast corner), C (east middle), D (southeast corner), E (southwest corner), and F (west middle)
- n = Global input MUX and pin number of the associated Global location m, either A0, A1, A2, B0, B1, B2, C0, C1, or C2. Refer to the "Global Resources in Low Power Flash Devices" section on page 47 for information about the three input pins per clock source MUX at CCC location m.
- u = I/O pair number in the bank, starting at 00 from the northwest I/O bank and proceeding in a clockwise direction
- x = P (Positive) or N (Negative) for differential pairs, or R (Regular—single-ended) for the I/Os that support single-ended and voltage-referenced I/O standards only
- w = D (Differential Pair), P (Pair), or S (Single-Ended). D (Differential Pair) if both members of the pair are bonded out to adjacent pins or are separated only by one GND or NC pin; P (Pair) if both members of the pair are bonded out but do not meet the adjacency requirement; or S (Single-Ended) if the I/O pair is not bonded out. For Differential (D) pairs, adjacency for ball grid packages means only vertical or horizontal. Diagonal adjacency does not meet the requirements for a true differential pair.
- B = Bank
- y = Bank number (0–7). The bank number starts at 0 from the northwest I/O bank and proceeds in a clockwise direction.
- $V = V_{REF}$
- z = V_{REF} minibank number (0–4). A given voltage-referenced signal spans 16 pins (typically) in an I/O bank. Voltage banks may have multiple V_{REF} minibanks.

DDR for Microsemi's Low Power Flash Devices

DDR Support in Flash-Based Devices

The flash FPGAs listed in Table 10-1 support the DDR feature and the functions described in this document.

Table 10-1 • Flash-Based FPGAs

Series	Family [*]	Description
IGLOO	IGLOO	Ultra-low power 1.2 V to 1.5 V FPGAs with Flash*Freeze technology
	IGLOOe	Higher density IGLOO FPGAs with six PLLs and additional I/O standards
	IGLOO nano	The industry's lowest-power, smallest-size solution
ProASIC3	ProASIC3	Low power, high-performance 1.5 V FPGAs
	ProASIC3E	Higher density ProASIC3 FPGAs with six PLLs and additional I/O standards
	ProASIC3 nano	Lowest-cost solution with enhanced I/O capabilities
	ProASIC3L	ProASIC3 FPGAs supporting 1.2 V to 1.5 V with Flash*Freeze technology
	RT ProASIC3	Radiation-tolerant RT3PE600L and RT3PE3000L
	Military ProASIC3/EL	Military temperature A3PE600L, A3P1000, and A3PE3000L
	Automotive ProASIC3	ProASIC3 FPGAs qualified for automotive applications
Fusion	Fusion	Mixed signal FPGA integrating ProASIC3 FPGA fabric, programmable analog block, support for ARM [®] Cortex [™] -M1 soft processors, and flash memory into a monolithic device

Note: *The device names link to the appropriate datasheet, including product brief, DC and switching characteristics, and packaging information.

IGLOO Terminology

In documentation, the terms IGLOO series and IGLOO devices refer to all of the IGLOO devices as listed in Table 10-1. Where the information applies to only one product line or limited devices, these exclusions will be explicitly stated.

ProASIC3 Terminology

In documentation, the terms ProASIC3 series and ProASIC3 devices refer to all of the ProASIC3 devices as listed in Table 10-1. Where the information applies to only one product line or limited devices, these exclusions will be explicitly stated.

To further understand the differences between the IGLOO and ProASIC3 devices, refer to the *Industry's Lowest Power FPGAs Portfolio*.

Device Programmers

Single Device Programmer

Single device programmers are used to program a device before it is mounted on the system board.

The advantage of using device programmers is that no programming hardware is required on the system board. Therefore, no additional components or board space are required.

Adapter modules are purchased with single device programmers to support the FPGA packages used. The FPGA is placed in the adapter module and the programming software is run from a PC. Microsemi supplies the programming software for all of the Microsemi programmers. The software allows for the selection of the correct die/package and programming files. It will then program and verify the device.

Single-site programmers

A single-site programmer programs one device at a time. Microsemi offers Silicon Sculptor 3, built by BP Microsystems, as a single-site programmer. Silicon Sculptor 3 and associated software are available only from Microsemi.

- Advantages: Lower cost than multi-site programmers. No additional overhead for programming on the system board. Allows local control of programming and data files for maximum security. Allows on-demand programming on-site.
- Limitations: Only programs one device at a time.
- Multi-site programmers

Often referred to as batch or gang programmers, multi-site programmers can program multiple devices at the same time using the same programming file. This is often used for large volume programming and by programming houses. The sites often have independent processors and memory enabling the sites to operate concurrently, meaning each site may start programming the same file independently. This enables the operator to change one device while the other sites continue programming, which increases throughput. Multiple adapter modules for the same package are required when using a multi-site programmer. Silicon Sculptor I, II, and 3 programmers can be cascaded to program multiple devices in a chain. Multi-site programmers, such as the BP2610 and BP2710, can also be purchased from BP Microsystems. When using BP Microsystems multi-site programmers, users must use programming adapter modules available only from Microsemi. Visit the Microsemi SoC Products Group website to view the part numbers of the desired adapter module:

http://www.microsemi.com/soc/products/hardware/program_debug/ss/modules.aspx.

Also when using BP Microsystems programmers, customers must use Microsemi programming software to ensure the best programming result will occur.

- Advantages: Provides the capability of programming multiple devices at the same time. No
 additional overhead for programming on the system board. Allows local control of
 programming and data files for maximum security.
- Limitations: More expensive than a single-site programmer
- Automated production (robotic) programmers

Automated production programmers are based on multi-site programmers. They consist of a large input tray holding multiple parts and a robotic arm to select and place parts into appropriate programming sockets automatically. When the programming of the parts is complete, the parts are removed and placed in a finished tray. The automated programmers are often used in volume programming houses to program parts for which the programming time is small. BP Microsystems part number BP4710, BP4610, BP3710 MK2, and BP3610 are available for this purpose. Auto programmers cannot be used to program RTAX-S devices.

Where an auto-programmer is used, the appropriate open-top adapter module from BP Microsystems must be used.

Programming Centers

Microsemi programming hardware policy also applies to programming centers. Microsemi expects all programming centers to use certified programmers to program Microsemi devices. If a programming center uses noncertified programmers to program Microsemi devices, the "Noncertified Programmers" policy applies.

Important Programming Guidelines

Preprogramming Setup

Before programming, several steps are required to ensure an optimal programming yield.

Use Proper Handling and Electrostatic Discharge (ESD) Precautions

Microsemi FPGAs are sensitive electronic devices that are susceptible to damage from ESD and other types of mishandling. For more information about ESD, refer to the *Quality and Reliability Guide*, beginning with page 41.

Use the Latest Version of the Designer Software to Generate Your Programming File (recommended)

The files used to program Microsemi flash devices (*.bit, *.stp, *.pdb) contain important information about the switches that will be programmed in the FPGA. Find the latest version and corresponding release notes at http://www.microsemi.com/soc/download/software/designer/. Also, programming files must always be zipped during file transfer to avoid the possibility of file corruption.

Use the Latest Version of the Programming Software

The programming software is frequently updated to accommodate yield enhancements in FPGA manufacturing. These updates ensure maximum programming yield and minimum programming times. Before programming, always check the version of software being used to ensure it is the most recent. Depending on the programming software, refer to one of the following:

- FlashPro: http://www.microsemi.com/soc/download/program_debug/flashpro/
- · Silicon Sculptor: http://www.microsemi.com/soc/download/program_debug/ss/

Use the Most Recent Adapter Module with Silicon Sculptor

Occasionally, Microsemi makes modifications to the adapter modules to improve programming yields and programming times. To identify the latest version of each module before programming, visit http://www.microsemi.com/soc/products/hardware/program_debug/ss/modules.aspx.

Perform Routine Hardware Self-Diagnostic Test

- Adapter modules must be regularly cleaned. Adapter modules need to be inserted carefully into the programmer to make sure the DIN connectors (pins at the back side) are not damaged.
- FlashPro

The self-test is only applicable when programming with FlashPro and FlashPro3 programmers. It is not supported with FlashPro4 or FlashPro Lite. To run the self-diagnostic test, follow the instructions given in the "Performing a Self-Test" section of http://www.microsemi.com/soc/documents/FlashPro_UG.pdf.

Silicon Sculptor

The self-diagnostic test verifies correct operation of the pin drivers, power supply, CPU, memory, and adapter module. This test should be performed with an adapter module installed and before every programming session. At minimum, the test must be executed every week. To perform self-diagnostic testing using the Silicon Sculptor software, perform the following steps, depending on the operating system:

- DOS: From anywhere in the software, type **ALT + D**.
- Windows: Click Device > choose Actel Diagnostic > select the Test tab > click OK.

Silicon Sculptor programmers must be verified annually for calibration. Refer to the *Silicon Sculptor Verification of Calibration Work Instruction* document on the website.

Programming Algorithm

JTAG Interface

The low power flash families are fully compliant with the IEEE 1149.1 (JTAG) standard. They support all the mandatory boundary scan instructions (EXTEST, SAMPLE/PRELOAD, and BYPASS) as well as six optional public instructions (USERCODE, IDCODE, HIGHZ, and CLAMP).

IEEE 1532

The low power flash families are also fully compliant with the IEEE 1532 programming standard. The IEEE 1532 standard adds programming instructions and associated data registers to devices that comply with the IEEE 1149.1 standard (JTAG). These instructions and registers extend the capabilities of the IEEE 1149.1 standard such that the Test Access Port (TAP) can be used for configuration activities. The IEEE 1532 standard greatly simplifies the programming algorithm, reducing the amount of time needed to implement microprocessor ISP.

Implementation Overview

To implement device programming with a microprocessor, the user should first download the C-based STAPL player or DirectC code from the Microsemi SoC Products Group website. Refer to the website for future updates regarding the STAPL player and DirectC code.

http://www.microsemi.com/soc/download/program_debug/stapl/default.aspx

http://www.microsemi.com/soc/download/program_debug/directc/default.aspx

Using the easy-to-follow user's guide, create the low-level application programming interface (API) to provide the necessary basic functions. These API functions act as the interface between the programming software and the actual hardware (Figure 15-2).

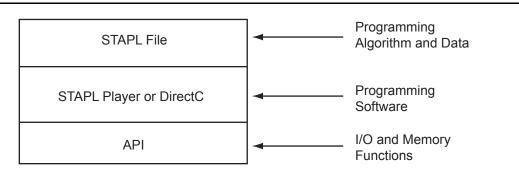


Figure 15-2 • Device Programming Code Relationship

The API is then linked with the STAPL player or DirectC and compiled using the microprocessor's compiler. Once the entire code is compiled, the user must download the resulting binary into the MCU system's program memory (such as ROM, EEPROM, or flash). The system is now ready for programming.

To program a design into the FPGA, the user creates a bitstream or STAPL file using the Microsemi Designer software, downloads it into the MCU system's volatile memory, and activates the stored programming binary file (Figure 15-3 on page 352). Once the programming is completed, the bitstream or STAPL file can be removed from the system, as the configuration profile is stored in the flash FPGA fabric and does not need to be reloaded at every system power-on.

Microprocessor Programming of Microsemi's Low Power Flash Devices

List of Changes

The following table lists critical changes that were made in each revision of the chapter.

Date	Changes	Page			
September 2012	The "Security" section was modified to clarify that Microsemi does not support read-back of FPGA core-programmed data (SAR 41235).	354			
July 2010	This chapter is no longer published separately with its own part number and version but is now part of several FPGA fabric user's guides.				
v1.4 (December 2008)	GLOO nano and ProASIC3 nano devices were added to Table 15-1 • Flash- Based FPGAs.				
v1.3 (October 2008)	The "Microprocessor Programming Support in Flash Devices" section was revised to include new families and make the information more concise.	350			
v1.2 (June 2008)	 The following changes were made to the family descriptions in Table 15-1 • Flash-Based FPGAs: ProASIC3L was updated to include 1.5 V. The number of PLLs for ProASIC3E was changed from five to six. 				
v1.1 (March 2008)	The "Microprocessor Programming Support in Flash Devices" section was updated to include information on the IGLOO PLUS family. The "IGLOO Terminology" section and "ProASIC3 Terminology" section are new.	350			

18 – Power-Up/-Down Behavior of Low Power Flash Devices

Introduction

Microsemi's low power flash devices are flash-based FPGAs manufactured on a 0.13 μ m process node. These devices offer a single-chip, reprogrammable solution and support Level 0 live at power-up (LAPU) due to their nonvolatile architecture.

Microsemi's low power flash FPGA families are optimized for logic area, I/O features, and performance. IGLOO[®] devices are optimized for power, making them the industry's lowest power programmable solution. IGLOO PLUS FPGAs offer enhanced I/O features beyond those of the IGLOO ultra-low power solution for I/O-intensive low power applications. IGLOO nano devices are the industry's lowest-power cost-effective solution. ProASIC3[®]L FPGAs balance low power with high performance. The ProASIC3 family is Microsemi's high-performance flash FPGA solution. ProASIC3 nano devices offer the lowest-cost solution with enhanced I/O capabilities.

Microsemi's low power flash devices exhibit very low transient current on each power supply during power-up. The peak value of the transient current depends on the device size, temperature, voltage levels, and power-up sequence.

The following devices can have inputs driven in while the device is not powered:

- IGLOO (AGL015 and AGL030)
- IGLOO nano (all devices)
- IGLOO PLUS (AGLP030, AGLP060, AGLP125)
- IGLOOe (AGLE600, AGLE3000)
- ProASIC3L (A3PE3000L)
- ProASIC3 (A3P015, A3P030)
- ProASIC3 nano (all devices)
- ProASIC3E (A3PE600, A3PE1500, A3PE3000)
- Military ProASIC3EL (A3PE600L, A3PE3000L, but not A3P1000)
- RT ProASIC3 (RT3PE600L, RT3PE3000L)

The driven I/Os do not pull up power planes, and the current draw is limited to very small leakage current, making them suitable for applications that require cold-sparing. These devices are hot-swappable, meaning they can be inserted in a live power system.¹

^{1.} For more details on the levels of hot-swap compatibility in Microsemi's low power flash devices, refer to the "Hot-Swap Support" section in the I/O Structures chapter of the FPGA fabric user's guide for the device you are using.

Power-Up/-Down Behavior of Low Power Flash Devices

Flash Devices Support Power-Up Behavior

The flash FPGAs listed in Table 18-1 support power-up behavior and the functions described in this document.

Table 18-1 • Flash-Based FPGAs

Series	Family [*]	Description
IGLOO	IGLOO	Ultra-low power 1.2 V to 1.5 V FPGAs with Flash*Freeze technology
	IGLOOe	Higher density IGLOO FPGAs with six PLLs and additional I/O standards
	IGLOO nano	The industry's lowest-power, smallest-size solution
	IGLOO PLUS	IGLOO FPGAs with enhanced I/O capabilities
ProASIC3	ProASIC3	Low power, high-performance 1.5 V FPGAs
	ProASIC3E	Higher density ProASIC3 FPGAs with six PLLs and additional I/O standards
	ProASIC3 nano	Lowest-cost solution with enhanced I/O capabilities
	ProASIC3L	ProASIC3 FPGAs supporting 1.2 V to 1.5 V with Flash*Freeze technology
	RT ProASIC3	Radiation-tolerant RT3PE600L and RT3PE3000L
	Military ProASIC3/EL	Military temperature A3PE600L, A3P1000, and A3PE3000L
	Automotive ProASIC3	ProASIC3 FPGAs qualified for automotive applications

Note: *The device names link to the appropriate datasheet, including product brief, DC and switching characteristics, and packaging information.

IGLOO Terminology

In documentation, the terms IGLOO series and IGLOO devices refer to all of the IGLOO devices as listed in Table 18-1. Where the information applies to only one product line or limited devices, these exclusions will be explicitly stated.

ProASIC3 Terminology

In documentation, the terms ProASIC3 series and ProASIC3 devices refer to all of the ProASIC3 devices as listed in Table 18-1. Where the information applies to only one product line or limited devices, these exclusions will be explicitly stated.

To further understand the differences between the IGLOO and ProASIC3 devices, refer to the *Industry's Lowest Power FPGAs Portfolio*.